

Incremental Gate Sizing for Late Process Changes

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Late process changes?

- Aggressive schedules = uncertainty
 - From ITRS 2008:

Table DESN9 Design for Manufacturability Technology Requirements

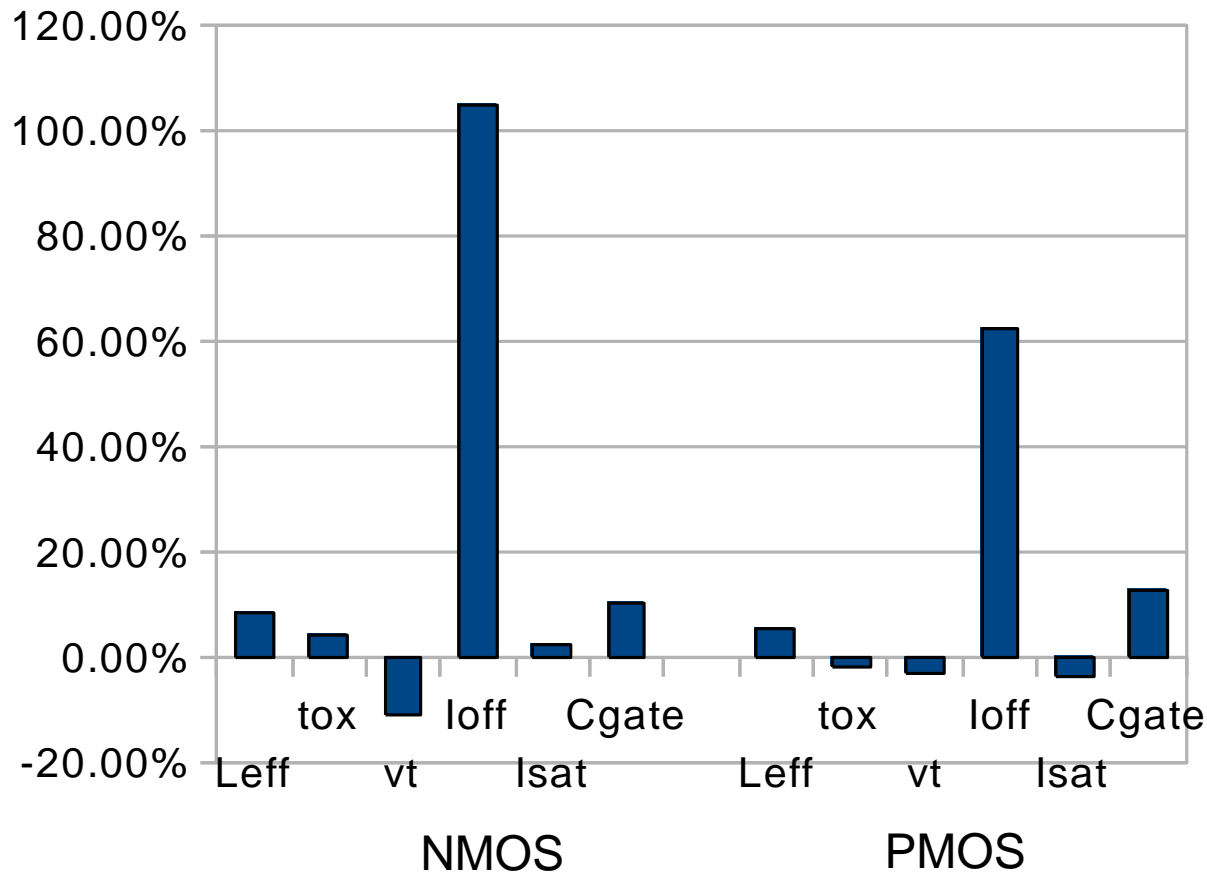
| <i>Year of Production</i> | <i>2007</i> | <i>2008</i> | <i>2009</i> | <i>2010</i> | <i>2011</i> | <i>2012</i> |
|---|-------------|-------------|-------------|-------------|-------------|-------------|
| Normalized mask cost from public and IDM data | 1 | 1.3 | 1.7 | 2.3 | 3 | 3.9 |
| % V_{dd} variability: % variability seen in on-chip circuits | 10% | 10% | 10% | 10% | 10% | 10% |
| % V_{th} variability: doping variability impact on V_{th} , (minimum size devices, memory) | 31% | 35% | 40% | 40% | 40% | 58% |
| % V_{th} variability: includes all sources | 33% | 37% | 42% | 42% | 42% | 58% |
| % V_{th} variability: typical size logic devices, all sources | 16% | 18% | 20% | 20% | 20% | 26% |
| % CD variability | 12% | 12% | 12% | 12% | 12% | 12% |
| % circuit performance variability circuit comprising gates and wires | 46% | 48% | 49% | 51% | 60% | 63% |
| % circuit total power variability circuit comprising gates and wires | 56% | 57% | 63% | 68% | 72% | 76% |
| % circuit leakage power variability circuit comprising gates and wires | 124% | 143% | 186% | 229% | 255% | 281% |

Solutions known, under development

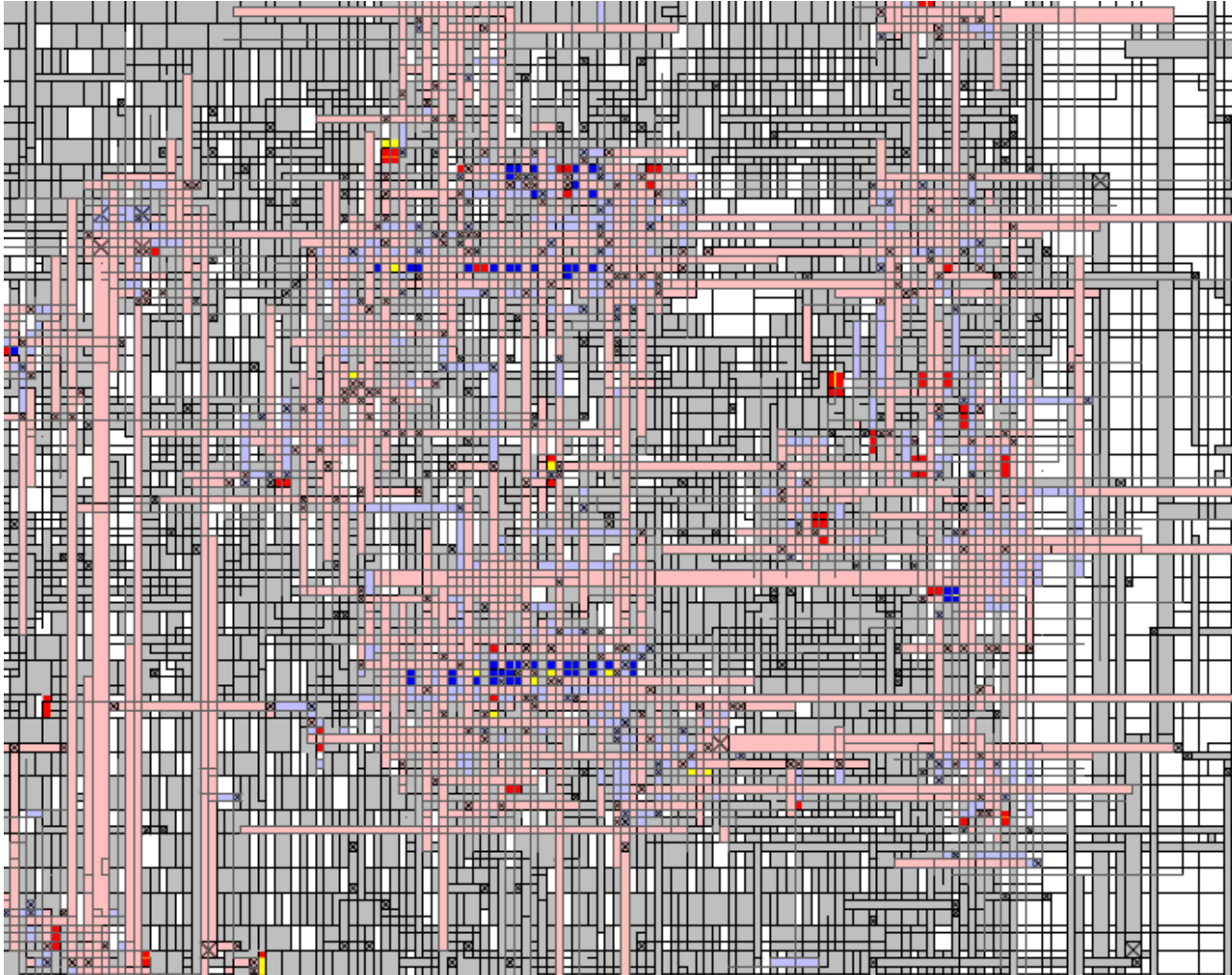
Solutions not known

45nm Process change example

- From April 2008 to March 2010



What does an ECO cost?



ECO Cost Measures

- **ECO Area Cost** – Changed area:
 - Amount of area that must be reanalyzed
 - Parasitic Extraction
 - LVS / DRC
 - Potential errors to be corrected
- **ECO Timing Cost** – Changed timing
 - The effect of the ECO on the timing signal
 - Changes flow downstream / upstream
 - Potential timing errors to be corrected

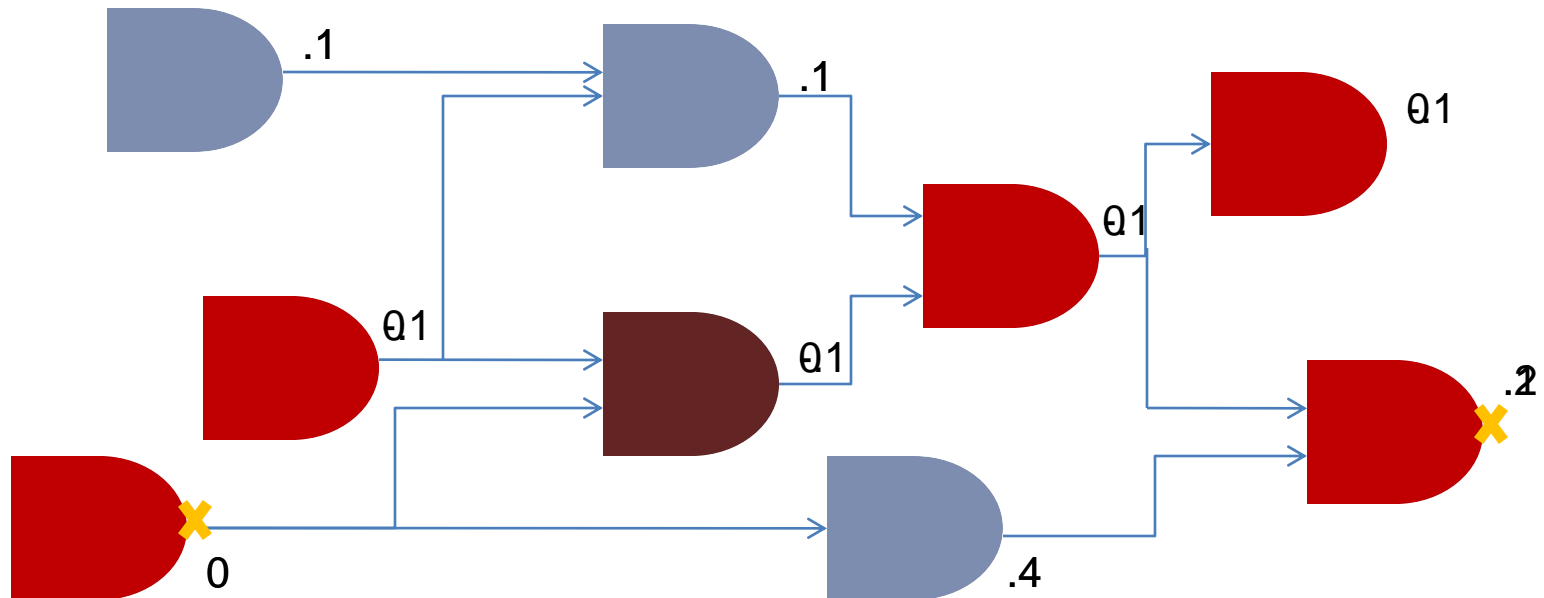
Modeling ECO Area Cost

- Eco Cost: amount of area, in μm^2 that has changed
 - Includes gate area, metal wires and vias
- Modeled as a linear function of:
 - Number of changed pins
 - Number dislocated pins
 - Old and new locations do not overlap
 - Area of the pin bounding box
 - Congestion over the pin bounding box



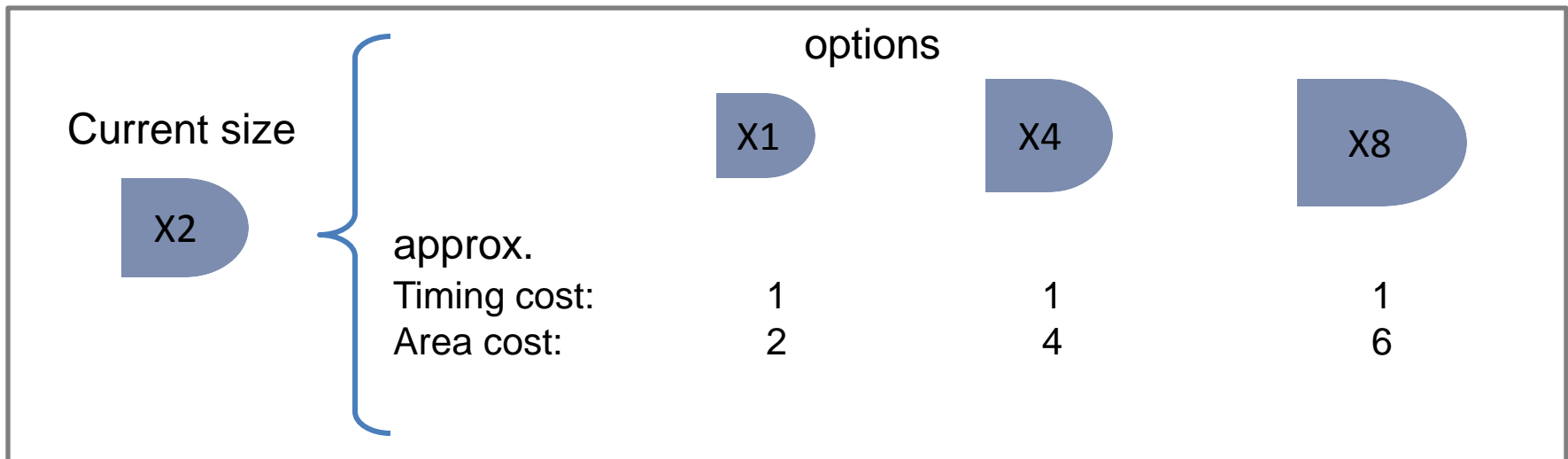
ECO Timing Cost

- Timing is affected downstream and upstream
- ECO Timing cost is defined as:
 - Number of non-critical pins that are upstream and downstream from an ECO



ECO-cost aware design via LPECO

- Linear programming based ECO gate sizing
 - Objective: ECO cost + Power cost
 - Constraints: Delay (timing closure)
- For timing **infeasible** problems:
 - Slack maximization

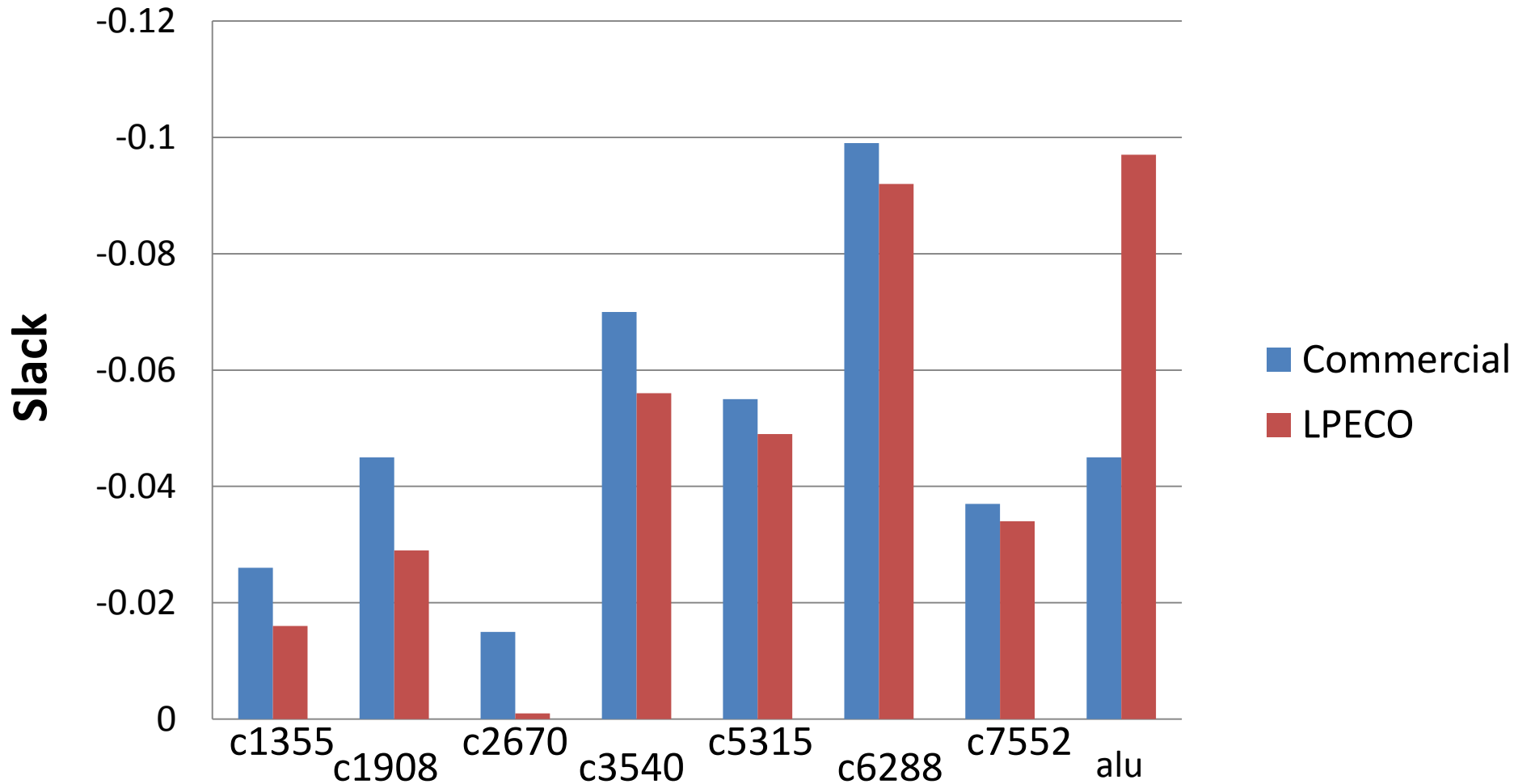


Experimental Setup

- 45nm Nangate Open Cell Library
- Manufacturing process change:

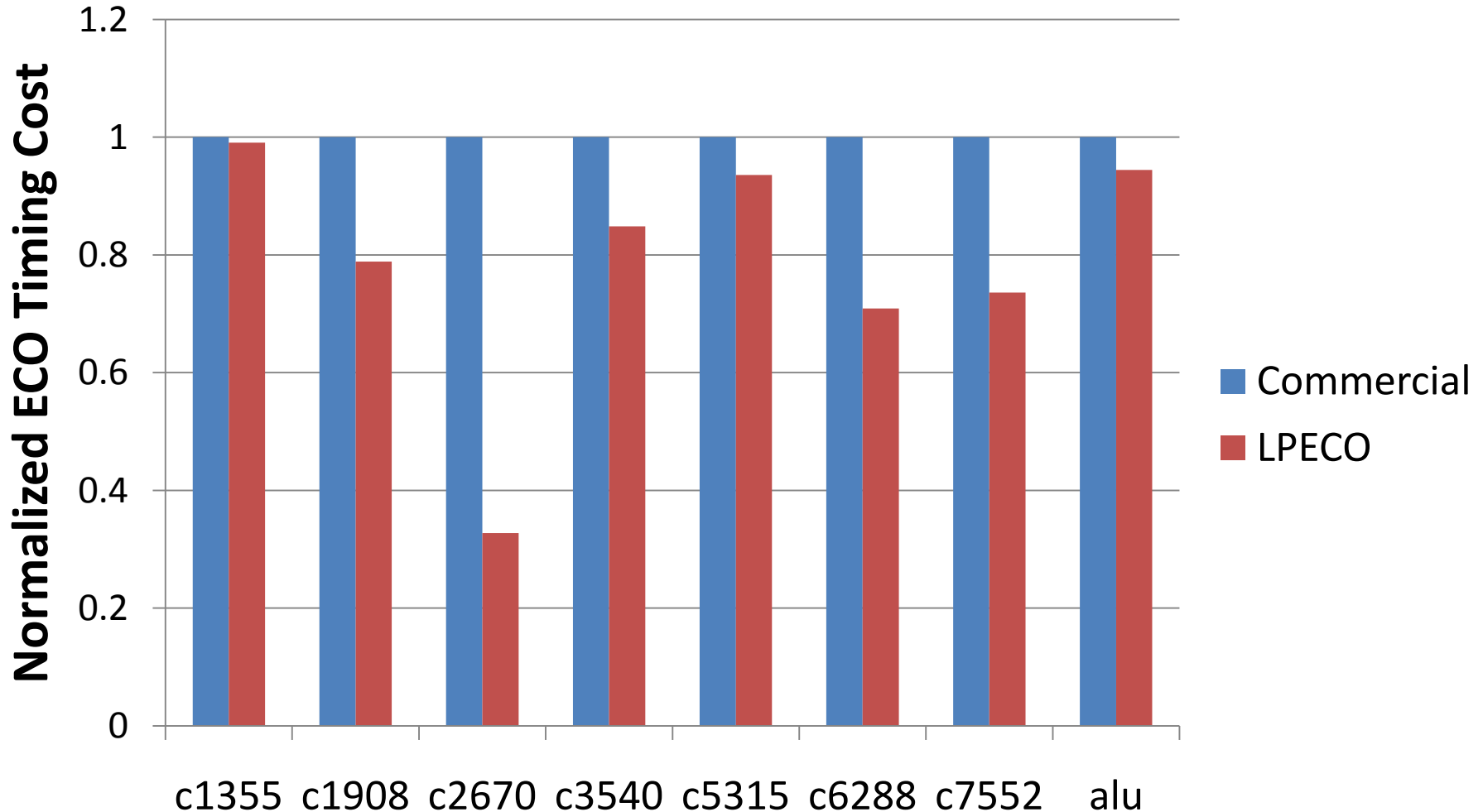
| | <u>Nmos</u> | <u>Pmos</u> |
|--------|-------------|-------------|
| Vt: | -10% | -5% |
| tox: | +5% | -5% |
| cgate: | +10% | +10% |
| leff: | +5% | +5% |

Results: Slack maximization (infeasible designs)



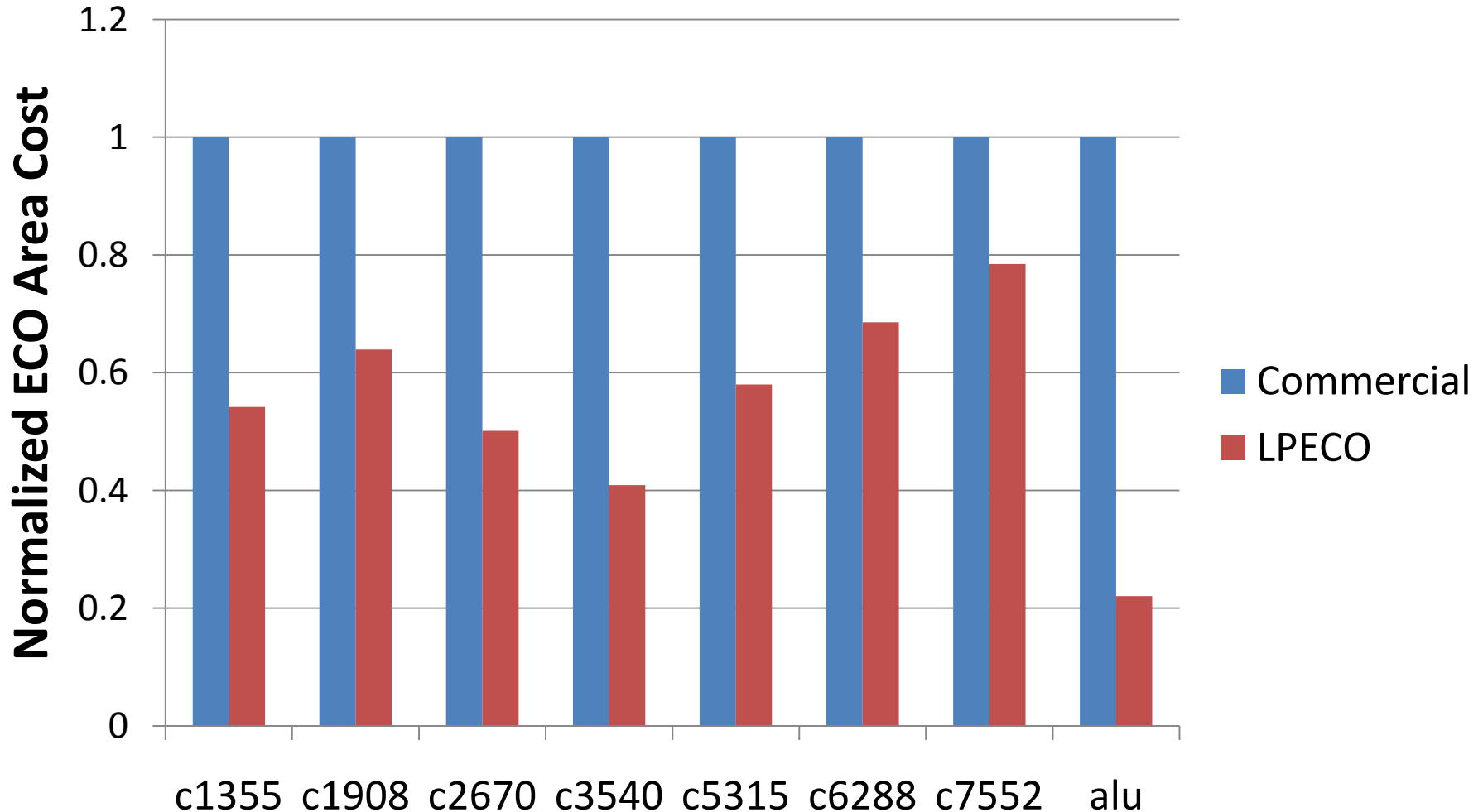
vt: nmos -10%, pmos -5%; tox: nmos +5%, pmos -5%;
cgate: nmos +10%, pmos +10%; leff: nmos +5%, pmos +5%

Results: Timing Cost Comparison



vt: nmos -10%, pmos -5%; tox: nmos +5%, pmos -5%;
cgate: nmos +10%, pmos +10%; leff: nmos +5%, pmos +5%

Results: Area Cost Comparison



vt: nmos -10%, pmos -5%; tox: nmos +5%, pmos -5%;
cgate: nmos +10%, pmos +10%; leff: nmos +5%, pmos +5%

Summary

- Quantified ECO Costs:
 - ECO Timing Cost
 - ECO Area Cost
- Performed incremental optimization to minimize ECO costs using LPECO
- Method performs well compared to commercial tool:
 - 22% to 88% reduction in ECO Area
 - 1% to 67% reduction in ECO Timing Cost
- Future goals:
 - Initial designs that incur small ECO penalties in the future
 - Large scale examples

Extra Slides

ECO-LP

$$\begin{aligned}
 & \text{minimize} && \sum_{i,k} p_{ik} y_{ik} + \gamma \text{ECO}(y; x) \\
 & \text{subject to} && t_i + d_{i0} + \sum_k \delta_{ik} y_{ik} \leq t_j, \quad \forall i \in \text{fo}(j) \\
 & && t_i \leq T_{\max}, \quad \forall i \in \text{po} \\
 & && \sum_k y_{ik} \leq 1, \quad \forall i \\
 & && \sum_k y_{ik} + \\
 & && \dots \sum_{j \in \text{fo}(i)} \sum_k y_{jk} + \sum_{j \in \text{fi}(i)} \sum_k y_{jk} \leq 1, \quad \forall i \\
 & && 0 \leq y_{ik} \leq 1
 \end{aligned} \tag{2}$$

The variables are:

- t_i : Arrival time for gate i
- d_{i0} : Current delay for gate i
- δ_{ik} : Change in the delay of gate i under size k
- y_{ik} : Assignment variable of gate i to size k
- p_{ik} : Power cost of changing gate i to size k